

# INTERNATIONAL STANDARD

## NORME INTERNATIONALE

**Integrated circuits – Measurement of electromagnetic immunity –  
Part 2: Measurement of radiated immunity – TEM cell and wideband TEM cell  
method**

**Circuits intégrés – Mesure de l'immunité électromagnétique –  
Partie 2: Mesure de l'immunité rayonnée – Méthode de cellule TEM et cellule  
TEM à large bande**



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**INTEGRATED CIRCUITS – MEASUREMENT OF  
ELECTROMAGNETIC IMMUNITY –**
**Part 2: Measurement of radiated immunity –  
TEM cell and wideband TEM cell method**

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The text of this standard is based on the following documents:

FDIS	Report on voting
47A/838/FDIS	47A/843/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

This part of IEC 62132 is to be read in conjunction with IEC 62132-1.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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# INTEGRATED CIRCUITS – MEASUREMENT OF ELECTROMAGNETIC IMMUNITY –

## Part 2: Measurement of radiated immunity – TEM cell and wideband TEM cell method

### 1 Scope

This International Standard specifies a method for measuring the immunity of an integrated circuit (IC) to radio frequency (RF) radiated electromagnetic disturbances. The frequency range of this method is from 150 kHz to 1 GHz, or as limited by the characteristics of the TEM cell.

### 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-131:2002, *International Electrotechnical Vocabulary (IEV) – Part 131: Circuit theory*

IEC 60050-161:1990, *International Electrotechnical Vocabulary (IEV) – Chapter 161: Electromagnetic compatibility*

IEC 61967-2, *Integrated circuits – Measurement of electromagnetic emissions, 150 kHz to 1 GHz – Part 2: Measurement of radiated emissions – TEM cell and wideband TEM cell method*

IEC 62132-1:2006, *Integrated circuits – Measurement of electromagnetic immunity, 150 kHz to 1 GHz – Part 1: General conditions and definitions*

### 3 Terms and definitions

For the purpose of this document, the definitions in IEC 62132-1, IEC 60050-131 and IEC 60050-161, as well as the following, apply.

#### 3.1

##### **transverse electromagnetic mode (TEM)**

waveguide mode in which the components of the electric and magnetic fields in the propagation direction are much less than the primary field components across any transverse cross-section

#### 3.2

##### **TEM waveguide**

open or closed transmission line system, in which a wave is propagating in the transverse electromagnetic mode to produce a specified field for testing purposes.